

Search Notes

Application/Control No.

10/760,505

Examiner

Lois Zheng

Applicant(s)/Patent under
Reexamination

HIRAIWA ET AL.

Art Unit

1742

SEARCHED

Class	Subclass	Date	Examiner
204	243.1	8/18/2006	LLZ
204	252	8/18/2006	LLZ
204	247	8/18/2006	LLZ
204	241	8/18/2006	LLZ
205	411	8/18/2006	LLZ
205	230	8/18/2006	LLZ
205	618-619	8/18/2006	LLZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	8/18/2006	LLZ
EAST Search	8/19/2006	LLZ